



PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION

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ATTORNEY DOCKET No.	SERIAL NO.		
9319A-000222 09/871,600			
APPLICANT			
ARAI, et al			
FILING DATE	GROUP		
5/31/2001	1755		

U.S. PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.	27	5,872,501	2/16/1999	Hamano et al		

FORE		T DOCUMENTS				
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes No
1.	SL	10-53844	2/24/1998	JAPAN		Abstract

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Ref. Desig.	Examiner's Initials		
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Sheet 1 of 1

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ATTORNEY DOCKET No.	SERIAL NO.		
9319A-000222 09/871,600			
APPLICANT			
Akira ARAI et al			
FILING DATE	GROUP		
May 31, 2001	1755		

U.S. P	ATENT DO	CUMENTS				
Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
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FOREIGN PATENT DOCUMENTS					34 × 8		
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	n No
1.	Il	EP 1 15 127 A	07/2001	Europe			
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1.	Sh	Wang, Z. et al, "High-coercivity (NdDy)2(FeNb)14B-ALPHA-Fe nanocrystalline alloys", Journal of Applied Physics, American Institute of Physics, New York, US, vol. 81, no. 8, PART 2B, 15 April 1997, pgs. 5097-5099.
2.	98	European Patent Office Search Report

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1-20-2002

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